


<b>Search Notes</b>  	<b>Application/Control No.</b>  10645434	<b>Applicant(s)/Patent Under Reexamination</b>  CHANG ET AL.
	<b>Examiner</b>  Bayat, Ali	<b>Art Unit</b>  2624

SEARCHED			
Class	Subclass	Date	Examiner
382	232,233,250,251,253,268	6/06/07	A.B
375	240.2,240.03,240.29	6/06/07	A.B
358	1.9,426.14	6/06/07	A.B

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (USPAT; USPGPUB; EPO;JPO;DERWENT; IBM-TDB) See text search history print out.	6/06/07	A.B

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
USPGPUB	See Interference search history print out.	6/06/07	A.B